

P-Channel Enhancement Mode Power MOSFET

DESCRIPTION

The HM4435B uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V.

GENERAL FEATURES

• $V_{DS} = -30V, I_{D} = -9.1A$

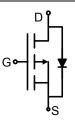
 $R_{DS(ON)} < 35m\Omega @ V_{GS} = -4.5V$

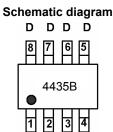
 $R_{DS(ON)}$ < 22m Ω @ V_{GS} =-10V

- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

Application

- Battery Switch
- Load switch
- Power management





Marking and pin Assignment



SOP-8 top view

Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
4435B	HM4435B	SOP-8	Ø330mm	12mm	2500 units

Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	-30	V
Gate-Source Voltage	V _{GS}	±20	V
Drain Current-Continuous	I _D	-9.1	Α
Drain Current-Pulsed (Note 1)	I _{DM}	-50	Α
Maximum Power Dissipation	P _D	3.1	W
Operating Junction and Storage Temperature Range	T_{J} , T_{STG}	-55 To 150	$^{\circ}$ C

Thermal Characteristic

Thermal Resistance, Junction-to-Ambient (Note 2)	R _{θJA}	40	°C/W
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-30	-33	-	V

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Page 1 v1.0



Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-30V,V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V		-	±100	nA
On Characteristics (Note 3)			•			
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=-250\mu A$	-1	-1.7	-3	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-9.1A	-	17	22	mΩ
Drain-Source On-State Resistance		V_{GS} =-4.5V, I_{D} =-6.9A	-	23	35	mΩ
Forward Transconductance	g FS	V _{DS} =-15V,I _D =-9.1A	10	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}	\/ - 4E\/\/ -0\/	-	1600	-	PF
Output Capacitance	C _{oss}	V_{DS} =-15V, V_{GS} =0V, F=1.0MHz	-	350	-	PF
Reverse Transfer Capacitance	C _{rss}	r – 1.0ivii iz	-	300	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	$t_{d(on)}$		-	10	-	nS
Turn-on Rise Time	t _r	V_{DD} =-15V, ID=-1A,	-	15	-	nS
Turn-Off Delay Time	$t_{d(off)}$	V_{GS} =-10 V , R_{GEN} =6 Ω	-	110	-	nS
Turn-Off Fall Time	t _f			70	-	nS
Total Gate Charge	Q_g	V _{DS} =-15V,I _D =-9.1A	-	30	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} 13V,109.1A V_{GS} 10V	-	5.5	-	nC
Gate-Drain Charge	Q _{gd}	v GS10 v	_	8	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-2.1A	-	-	-1.2	V

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

Page 2 v1.0

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

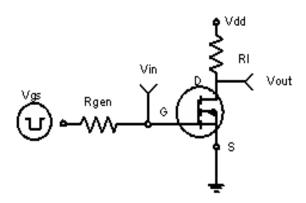
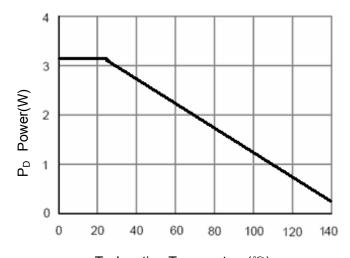


Figure 1:Switching Test Circuit



 T_J -Junction Temperature(${}^{\circ}C$)

Figure 3 Power Dissipation

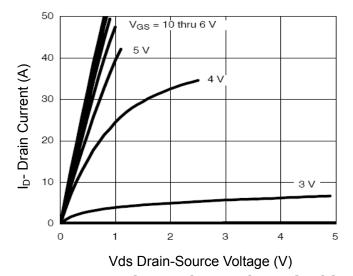


Figure 5 Output CHARACTERISTICS

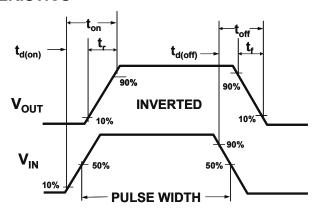


Figure 2:Switching Waveforms

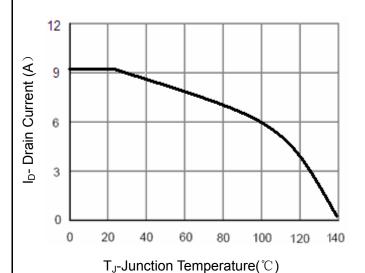


Figure 4 Drain Current

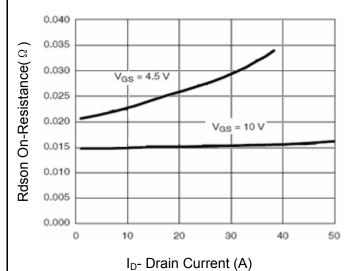


Figure 6 Drain-Source On-Resistance

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Page 3 v1.0

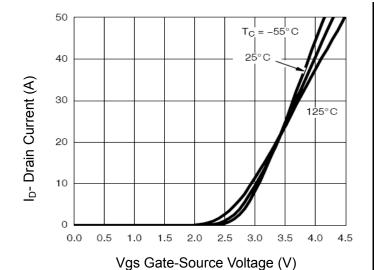


Figure 7 Transfer Characteristics

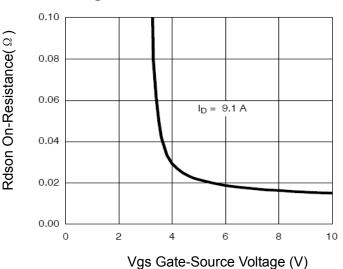


Figure 9 Rdson vs Vgs

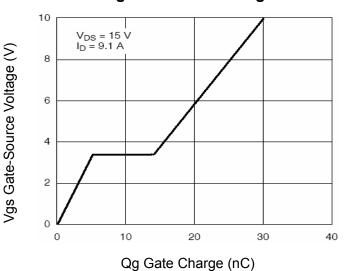


Figure 11 Gate Charge

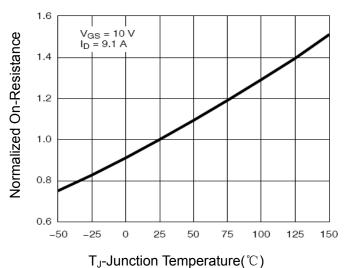
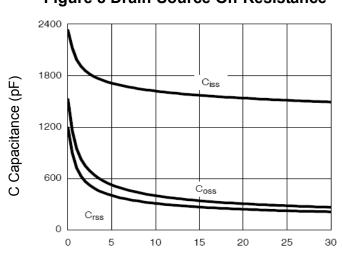


Figure 8 Drain-Source On-Resistance



Vds Drain-Source Voltage (V)

Figure 10 Capacitance vs Vds

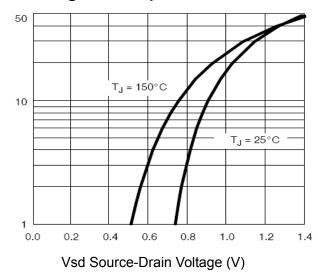
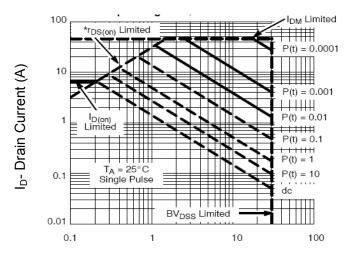


Figure 12 Source- Drain Diode Forward

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Is- Reverse Drain Current (A)

Page 4 v1.0



Vds Drain-Source Voltage (V)

Figure 13 Safe Operation Area

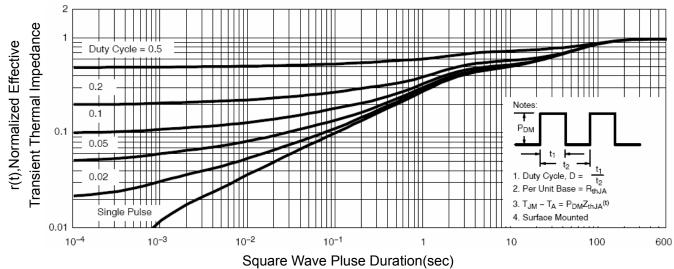
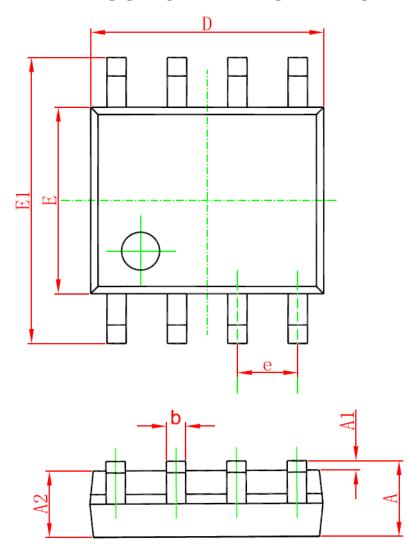
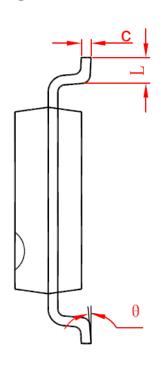


Figure 14 Normalized Maximum Transient Thermal Impedance

SOP-8 PACKAGE IN FORMATION





Ch l	Dimensions In	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0.004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
Е	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	

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Page 6 v1.0

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